# MSKSEMI















**ESD** 

TVS

TSS

MOV

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Semiconductor

## **VOLTAGE RANGE** 50 to 1000 Volts **CURRENT** 2.0 Ampere



**SMB** 

### **FEATURES**

- \* Ideal for surface mount applications
- \* Easy pick and place
- \* Built-in strain relief
- \* Low forward voltage drop

### **MECHANICAL DATA**

- \* Case: Molded plastic
- \* Epoxy: UL 94V-0 rate flame retardant
- \* Metallurgically bonded construction
- \* Polarity: Color band denotes cathode end
- \* Mounting position: Any
- \* Weight: 0.093 grams

## MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

Rating 25°C ambient temperature unless otherwies specified. Single phase half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%.

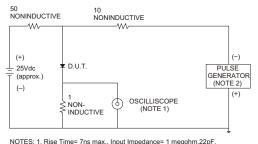
P/N(MARK)	US2AE	US2BB	US2DB	US2EB	US2GB	US2JB	US2KB	US2MB	UNITS
Maximum Recurrent Peak Reverse Voltage		100	200	300	400	600	800	1000	V
Maximum RMS Voltage		70	140	210	280	420	560	700	V
Maximum DC Blocking Voltage		100	200	300	400	600	800	1000	V
Maximum Average Forward Rectified Current		•	•	•					
.375"(9.5mm) Lead Length at Ta=50°C		2.0					Α		
Peak Forward Surge Current, 8.3 ms single half sine-wave									
superimposed on rated load (JEDEC method)		60					Α		
Maximum Instantaneous Forward Voltage at 2.0A		1.0 1.3				1.7		V	
Maximum DC Reverse Current Ta=25°C				5	.0				μА
at Rated DC Blocking Voltage Ta=100°C				15	50				μА
Maximum Reverse Recovery Time (Note 1)		50 75				nS			
Typical Junction Capacitance (Note 2)		30					pF		
Operating and Storage Temperature Range TJ, Tstg		-65—+150					°C		

#### NOTES:

- 1. Reverse Recovery Time test condition: IF=0.5A, IR=1.0A, IRR=0.25A
- 2. Measured at 1MHz and applied reverse voltage of 4.0V D.C.

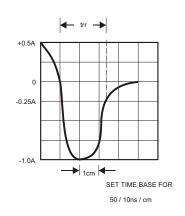
### RATING AND CHARACTERISTIC CURVES (US2AB THRU US2MB)

FIG.3- TEST CIRCUIT DIAGRAM AND REVERSE RECOVERY TIME CHARACTERISTICS

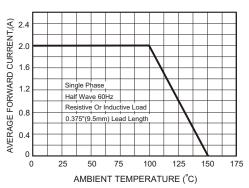


NOTES: 1. Rise Time= /ns max., Input Impedance= 1 megohm.23

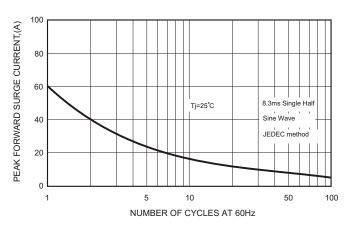
2. Rise Time= 10ns max., Source Impedance= 50 ohms.



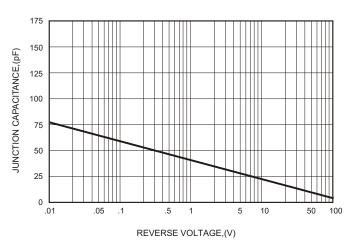
# FIG.2-TYPICAL FORWARD CURRENT DERATING CURVE



# FIG.4-MAXIMUM NON-REPETITIVE FORWARD SURGE CURRENT

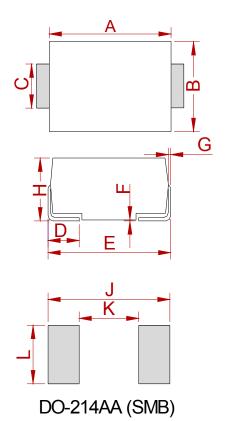


#### FIG.5-TYPICAL JUNCTION CAPACITANCE





## PACKAGE MECHANICAL DATA



	Dimensions					
Ref.	Millimeters		Inches			
	Min.	Max.	Min.	Max.		
Α	4.25	4.75	0.167	0.187		
В	3.30	3.94	0.130	0.155		
С	1.85	2.21	0.073	0.087		
D	0.76	1.52	0.030	0.060		
Е	5.08	5.59	0.200	0.220		
F	0.051	0.203	0.002	0.008		
G	0.15	0.31	0.006	0.012		
Н	2.11	2.44	0.083	0.096		
J	6.80		0.270			
K		2.60		0.100		
L	2.40		0.090			

## **REEL SPECIFICATION**

P/N	PKG	OTY
1 /11	1110	QII
PxxxxSB-MS	SMB	3000





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